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	Application No.	Applicant(s)	m
Notice of Allowability	09/437,469	DE RENZIS, ANTONIO	
	Examiner	Art Unit	
	Amanda H. Merlino	2877	
The MAILING DATE of this communication apperature All claims being allowable, PROSECUTION ON THE MERITS IS herewith (or previously mailed), a Notice of Allowance (PTOL-85) NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT R of the Office or upon petition by the applicant. See 37 CFR 1.313	(OR REMAINS) CLOSED in to or other appropriate communication is suitable.	his application. If not included lication will be mailed in due cour	se. THIS
1. This communication is responsive to <u>amendment filed 7/1</u>	<u>1/05</u> .		
2. The allowed claim(s) is/are <u>1,2,5,6,8-15,18 and 20-24.</u>			
3. ☐ Acknowledgment is made of a claim for foreign priority unallow All b) ☐ Some* c) ☐ None of the:		(f).	
Certified copies of the priority documents have			
2. Certified copies of the priority documents have	, ,		
3. Copies of the certified copies of the priority do	cuments have been received	in this national stage application f	from the
International Bureau (PCT Rule 17.2(a)).			
* Certified copies not received:			
Applicant has THREE MONTHS FROM THE "MAILING DATE" noted below. Failure to timely comply will result in ABANDONN THIS THREE-MONTH PERIOD IS NOT EXTENDABLE.		a reply complying with the require	ments
4. A SUBSTITUTE OATH OR DECLARATION must be subminformal PATENT APPLICATION (PTO-152) which give			CE OF
5. CORRECTED DRAWINGS (as "replacement sheets") mus	st be submitted.	•	
(a) including changes required by the Notice of Draftspers		(PTO-948) attached	
1) hereto or 2) to Paper No./Mail Date			
(b) ☐ including changes required by the attached Examiner Paper No./Mail Date		n the Office action of	
Identifying indicia such as the application number (see 37 CFR 1 each sheet. Replacement sheet(s) should be labeled as such in the same of			k) of
6. DEPOSIT OF and/or INFORMATION about the deposit attached Examiner's comment regarding REQUIREMENT			the
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Attachment(s)	·	annel Detect Accellent (DTC 47)	0)
1. Notice of References Cited (PTO-892)		ormal Patent Application (PTO-15)	2)
2. Notice of Draftperson's Patent Drawing Review (PTO-948)	6. ☐ Interview Sur Paper No /M	nmary (PTO-413), lail Date	
3. Information Disclosure Statements (PTO-1449 or PTO/SB/0 Paper No./Mail Date	08), 7. ☐ Examiner's A	mendment/Comment	
4. Examiner's Comment Regarding Requirement for Deposit	8. 🛭 Examiner's S	tatement of Reasons for Allowan	се
of Biological Material	9. 🗌 Other		

Allowable Subject Matter

Claims 1-2, 5-6, 8-15, 18, and 20-24 allowed.

The following is an examiner's statement of reasons for allowance:

As to claims 1-2, 5-6, 9-15, and 20-24 the prior art of record, taken alone or in combination, fails to disclose or render obvious a method for measuring distance comprising steps of carrying out a sampling of an analogue electric signal representative of a distance traveled by the emitted signal and the object diffused signal, so as to extract at least one sample x_k , representative of at least one respect point of the scanning line and converting the sampled analogue signal into a digital signal so as to obtain a numerical value of said at least one sample x_k wherein prior to the above step, there is a measuring device calibrations step so as to associate at least one calibration sample x_j of a calibration distance signal and a respective numerical value of said at least one sample x_j with a prefixed distance value..., in combination with the rest of the limitations of claim 1.

As to claims 18, the prior of record, taken alone or in combination, fails to disclose or render obvious a method for measuring distance comprising a calibration step wherein a prefixed distance is associated with a prefixed comparison signal by scanning light along the sample and then filling with the distance values associated to the numerical values obtained for the samples x_j , the items of a calibration matrix having, as index of column j a number from zero to the number of samples x_j extracted, and as index of row I, a number from zero to the maximum value of the numerical value obtained after the analog to digital conversion of the comparison signal, the method

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further comprising the step of filling the empty items (i, j) of the matrix comprises the step of identifying column by column, the empty items (I, j) of the matrix and filling each of these empty items with a value obtained by linearly interpolating between the two numerical values differing from 0 that are nearer to the empty item, and belonging to the same column, in combination with the rest of the limitations of the claim.

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Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

Conclusion

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Amanda H. Merlino whose telephone number is 571-272-2421. The examiner can normally be reached on Monday and Thursday.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Gregory J. Toatley, Jr. can be reached on 571-272-2800 ext 77. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

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Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

Amanda H Merlino Patent Examiner Art Unit 2877 September 29, 2005

Gregory J. Toatley, Jr. Supervisory Patent Examiner